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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Mitchell, et al.

Serial No.: 10/058,544

Filed:

For:

01/25/02

Multiple Contact Vertical Probe Solution Enabling Kelvin Connection

Benefits for Conductive Bump Testing

**Election** 

Commissioner of Patents

P.O. Box 1450

Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(A)

Docket No. TI-32531

Examiner:

Art Unit:

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as First Class Mail in an envelope addressed to: Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-

Elizabeth Austin

Dear Sir:

The following amendments and remarks are offered in response to the Examiner's Office Action dated 05/07/2003. They are respectfully submitted as a full and complete response to that Action.

The Examiner has required restriction to one of the species as follows:

The species of Figure 3; and the species of Figure 5.

**Election** 

Applicant elects to prosecute Claims 1-22 directed to the species of

Figure 5.

Figure 3 shows that two locations in a probe card include two parallel

probe needles. Figure 5 shows that two locations in a probe card include three

parallel probe needles. Figure 3 is thus a subset of Figure 5, so Applicant has

elected to prosecute the species of Figure 5. Claims 1-22 are not limited to two

probes, but instead refer to "at least two" or to "a second" conductive probe.

Thus all of claims 1-22 apply to the three probe embodiment of Figure 5,

whereas some of those claims may not apply to the two probe embodiment of

Figure 3.

Perhaps the Examiner intended a restriction between inventions, in which

case the Examiner is invited to call Applicant to discuss such a restriction.

If the Examiner has any questions or other correspondence regarding this

application, Applicant requests that the Examiner contact Applicant's attorney at

the below listed telephone number and address.

Respectfully submitted,

Michael K. Skrehot

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